

APPROVAL SHEET

WW25Q

±1%, ±5%

Metal low ohm power chip resistors

Size 2512 (6432), 1W

Sensing Type



FEATURE

- 1. Ultra low and stable TCR performance
- 2. High power rating and compact size
- 3. High reliability and stability
- 4. Reduced size of final equipment
- 5. RoHS compliant & Lead free
- 6. Excellent Heat dissipation and inrush withstand

APPLICATION

- Power supply
- PDA
- Digital meter
- Computer
- Automotives
- · Battery charger
- DC-DC power converter

DESCRIPTION

The resistors are constructed in a high grade low resistive metal body. The structure applies no trimming configuration to provide excellent heat dissipation and inrush withstand capability. The resistive layer is covered with a protective coat and printed a resistance marking code over it. Finally, the two external end terminations are added. For ease of soldering the outer layer of these end terminations is a Lead free terminations.



Fig 1. Construction of Chip-R

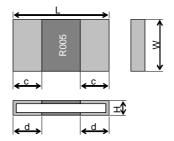


QUICK REFERENCE DATA

Item	General Specification		
Series No.	WW	25Q	
Size code	2512 (6432)		
Resistance Tolerance	±5% , ±1%		
Resistance Range	1mΩ 2mΩ ~ 15mΩ		
TCR (ppm/°C)	±75 ppm/°C ±100 ppm/°C		
Max. power at T _{amb} =70°C	1 W		
Max. Operation Current (DC or RMS)	31.6A ~ 8.16A		
Climatic category (IEC 60068)	55/15	5/56	

Note: Max. Operation Current: So called RCWC (Rated Continuous Working Current) is determined by

 $RCWC = \sqrt{Rated Power / Resistance Value}$ listed above.



MECHANICAL DATA (unit: mm)

Туре	Size (inch)	Resistance	L (mm)	W (mm)	H (mm)	C (mm)	D (mm)
		1mΩ	6.3±0.25	3.2±0.25	0.38±0.15	2.20	<u>+</u> 0.25
		2mΩ				1.10:	<u>+</u> 0.25
		3mΩ			0.48±0.15	1.10:	<u>+</u> 0.25
		4mΩ			0.37±0.15	2.20	<u>+</u> 0.25
		5mΩ				1.95:	<u></u> ±0.25
		6mΩ				1.75±0.25	
WW25Q	2512	7mΩ			0.34±0.15	1.40:	<u>+</u> 0.25
		8mΩ				1.10:	<u></u> ±0.25
		9mΩ		3.1±0.25		0.90	<u>+</u> 0.25
		10mΩ				1.75:	<u>+</u> 0.25
		11mΩ				1.55:	<u>+</u> 0.25
	13m	12mΩ			0.00.045	1.35:	±0.25
		13mΩ			0.23±0.15	1.25:	±0.25
		14mΩ				1.05:	±0.25
		15mΩ				0.95	<u>+</u> 0.25



MARKING

Each resistor is marked with a four-digit code on the protective coating to designate the nominal resistance value.

Example:

 $R005 = 0.005\Omega$ $R010 = 0.010\Omega$

FUNCTIONAL DESCRIPTION

Derating curve

The power that the resistor can dissipate depends on the operating temperature; see Fig.2

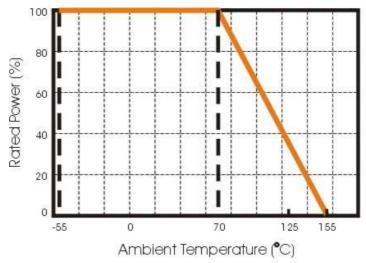


Fig.2 Maximum dissipation in percentage of rated power As a function of the ambient temperature

MOUNTING

Due to their rectangular shapes and small tolerances, Surface Mountable Resistors are suitable for handling by automatic placement systems.

Chip placement can be on ceramic substrates and printed-circuit boards (PCBs).

Electrical connection to the circuit is by individual soldering condition.

The end terminations guarantee a reliable contact.



SOLDERING CONDITIONS

The robust construction of chip resistors allows them to be completely immersed in a solder bath of 260°C for 10 seconds. Therefore, it is possible to mount Surface Mount Resistors on one side of a PCB and other discrete components on the reverse (mixed PCBs).

Surface Mount Resistors are tested for solderability at 235°C during 2 seconds within lead-free solder bath. The test condition for no leaching is 260°C for 30 seconds. Typical examples of soldering processes that provide reliable joints without any damage are given in Fig

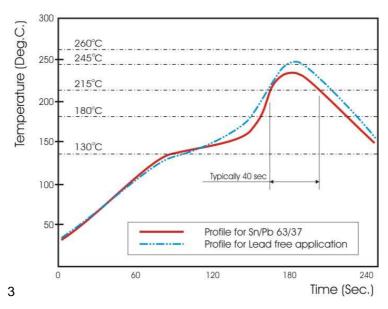


Fig 3. Infrared soldering profile for Chip Resistors WW25Q

CATALOGUE NUMBERS

The resistors have a catalogue number starting with .

WW25	Q	R005	J	Т	L
Size code	Type code	Resistance code	Tolerance	Packaging code	Termination code
WW25 : 2512	Q : 1W	R is first digit followed by 3 significant digits. $0.010\Omega = R010$ $0.005\Omega = R005$	J : ±5% F : ±1%	T:7" reeled in tape	L = Sn base (lead free)

Reeled tape packaging : 12mm width embossed taping 4,000pcs per reel.



TEST & REQUIREMENTS (JIS C 5201-1: 1998)

Table- 4(1)

No.	Test items	Condition of test (JIS C 5201–1)	Performance requirements	
1	Visual examination	Sub-clause 4.4.1	As in 4.4.1	
		Checked by visual examination.	The marking shall be legible, as	
			checked by visual examination.	
2	Dimension	Sub-clause 4.4.2	As specified in Table-3 of this	
	Danistanas	D : ()	specification.	
	Resistance	Resistance value shall be measured by mounting	As in 4.5.2	
		the substrate of the following condition.	The resistance value shall correspond with the rated resistance	
		Current Current	taking into account the specified	
		terminal terminal	tolerance	
		:Copper dad		
		Voltage terminal :Solder resist		
		a: 3mm (1m Ω), 2.6mm (5m Ω),		
		1.8mm (10m Ω ,15m Ω)		
		Thickness of copper clad: 0.035mm		
		4-Terminal method		
		Measurement current: 1(A)		
		Note: The measuring apparatus corresponding to		
		DC Low-ohm Mater (1A) of AX-1152D for ADEX CORPORATION.		
3	Voltage proof	Sub-clause 4.7		
ľ	voltage proof	Method: 4.6.1.4(See Figure–5)	No breakdown or flash over	
		Test voltage: Alternating voltage with a peak value		
		of 1.42 times the insulation voltage.		
		Duration: 60 s±5 s		
		Insulation resistance		
		Test voltage: Insulation voltage	R≥1GΩ	
4	Coldonal III.	Duration: 1 min.	A - :- A 47 A F	
4	Solderability	Sub-clause 4.17	As in 4.17.4.5 The terminations shall be covered	
		Without aging Flux: The resistors shall be immersed in a	with a smooth and bright solder	
		non-activated soldering flux for 2 s.	coating.	
		Bath temperature: 235 °C±5 °C	g	
		Immersion time: 2 s±0.5 s		
5	Mounting	Sub-clause 4.31		
		Substrate material: Epoxide woven glass		
		Test substrate: Figure-3		
	Overload	Sub-clause 4.13		
	(in the mounted state)	The applied voltage shall be 2.5 times the rated		
		voltage or the current corresponding to.		
		Duration: 2 s Visual examination		
		Resistance	No visible damage	
		Sub-clause 4.30	ΔR≤±1%	
	Solvent resistance of the	Solvent: 2–propanol	Legible marking	
	marking	Solvent temperature: 23 °C±5 °C		
		Method 1		
		Rubbing material: cotton wool		
		Without recovery		



Table-4(2)

No	Test items	Condition of test (JIS C 5201-1)	Performance requirements
6	Mounting	Sub-clause 4.31	
		Substrate material: Epoxide woven glass	
		Test substrate: Figure-4	
	Bound strength of the end	Sub-clause 4.33	
	face plating	Bent value: 1 mm	
		Resistance	ΔR≤±1%
	Final measurements	Sub-clause 4.33.6	
		Visual examination	No visible damage
7	Resistance to soldering heat	Sub-clause 4.18	
		Solder temperature: 260 °C±5 °C	
		Immersion time: 10 s±0.5 s	
		Visual examination	As in 4.18.3.4
			No sign of damage such as cracks.
			ΔR≤±1%
	Component solvent	r colour roo	
	resistance	Sub-clause 4.29	
		Solvent: 2-propanol	
		Solvent temperature: 23 °C±5 °C	
		Method 2	Na visible demons
		Recovery: 48 h	No visible damage ΔR ≤ ±1%
		Visual examination	ΔR ≥ ±170
8	Mounting	Resistance	
l°	Mounting	Sub-clause 4.31	
		Substrate material: Epoxide woven glass Test substrate: Figure–3	
	Adhesion	Sub-clause 4.32	
	Adilesion	Sub-clause 4.32 Force: 5 N	
		Duration: 10 s±1 s	
		Visual examination	No visible damage
	Rapid change temperature	Sub-clause 4.19	
3		Lower category temperature:-55 °C	
		Upper category temperature:+155 °C	
		Duration of exposure at each temperature: 30	
		min.	
	Number of cycles: 5 cycles.		
		Visual examination	No visible damage
		Resistance	ΔR≤±1%



Table-4(3)

No	Test items	Condition of test (JIS C 5201–1)	Performance requirements
9	Climatic sequence	Sub-clause 4.23	'
-	-Dry heat	Sub-clause 4.23.2	
	ĺ	Test temperature: +155 °C	
		Duration: 16 h	
	-Damp heat, cycle	Sub-clause 4.23.3	
	(12+12hour cycle)	Test method: 2	
	First cycle	Test temperature: 55 °C	
		[Severity(2)]	
	-Cold	Sub-clause 4.23.4	
		Test temperature –55 °C	
		Duration: 2h	
	–Damp heat, cycle	Sub-clause 4.23.6	
	(12+12hour cycle)	Test method: 2	
	Remaining cycle	Test temperature: 55 °C	
		[Severity (2)]	
		Number of cycles: 5 cycles	
	–D.C. load	Sub-clause 4.23.7	
		The applied current shall be the rated current.	
		Duration: 1 min.	
		Visual examination	No visible damage
		Resistance	ΔR≤±5%
10	Mounting	Sub-clause 4.31	
		Substrate material: Epoxide woven glass	
		Test substrate: Figure-3	
	Endurance at 70 °C	Sub-clause 4.25.1	
		Ambient temperature: 70 °C±2 °C	
		Duration: 1000 h	
		The current shall be applied in cycles of 1.5 h	
		on and 0.5 h.	
		The applied current shall be the rated current	
		Examination at 48 h, 500 h and	
		1000 h:	
		Visual examination	No visible damage
		Resistance	ΔR≤±5%
		I	A1121370



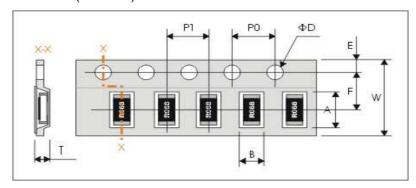
Table-4(4)

	Table 4(4)						
No	Test items	Condition of test (JIS C 5201–1)	Performance requirements				
11	Mounting	Sub-clause 4.31 Substrate material: Epoxide woven glass Test substrate: Figure–3					
	Variation of resistance with temperature	Sub-clause 4.8 +20 °C / +155 °C	As in Table–1				
12	Mounting	Sub-clause 4.31 Substrate material: Epoxide woven glass Test substrate: Figure–3					
	Damp heat, steady state	Sub-clause 4.24 Ambient temperature: 40 °C±2 °C Relative humidity: 93 ½ % Without current applied. Visual examination	No visible damage Legible marking				
		Resistance	ΔR≤±5%				
13	Dimensions (detail)	Sub-clause 4.4.3	As in Table–4				
	Mounting	Sub-clause 4.31 Substrate material: Epoxide woven glass Test substrate: Figure–3					
	Endurance at upper category temperature	Sub-clause 4.25.3 Ambient temperature:155 °C±2 °C Duration: 1000 h Examination at 48 h, 500 h and 1000 h: Visual examination Resistance	No visible damage Δ R ≤ ±5%				



PACKAGING

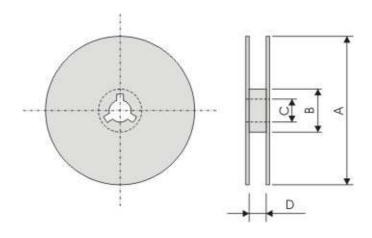
Plastic Tape specifications (unit :mm)



Symbol	Α	В	W	F	E
Dimensions	6.90±0.20	3.60±0.20	12.00±0.30	5.50±0.05	1.75±0.10

Symbol	P1	P0	ΦD	Т
Dimensions	4.00±0.10	4.00±0.10	$\Phi 1.50^{+0.1}_{-0.0}$	1.10±0.15

Reel dimensions



Symbol	Α	В	С	D
(unit : mm)	Ф180.0 -1.5	Φ60.0±1.0	13.0±0.2	13.0±1.0

Taping quantity

- Chip resistors 4,000 pcs per reel.

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